# 2SK3995

# Silicon N-channel enhancement MOSFET

For high speed switching circuits For PDP

### Features

- Medium breakdown voltag:  $V_{DSS} = 200 \text{ V}, I_D = 30 \text{ A}$
- Low ON resistance, optimum for PDP panel drive

#### Absolute Maximum Ratings $T_a = 25^{\circ}C$

Parameter	Symbol	Rating	Unit	
Drain-source surrender voltage	V <sub>DSS</sub>	200	V	
Gate-source surrender voltage	V <sub>GSS</sub>	±30	V	
Drain current	ID	30	А	
Peak drain current *1	I <sub>DP</sub>	120	Α	
Drain reverse current	I <sub>DR</sub>	30	Α	
Peak drain reverse current *1	I <sub>DRP</sub>	120	A	
Avalanche energy capability *2	EAS	801	mJ	
Drain power dissipation $\frac{T_{C} = 25^{\circ}C}{T_{a} = 25^{\circ}C^{*3}}$	P <sub>D</sub>	50	W	
Drain power dissipation $T_a = 25^{\circ}C^{*3}$		1.4	W	
Junction temperature	Tj	150	<b>3</b> °	
Storage temperature	T <sub>stg</sub>	-55 to +150	S °C S	



- TO-220C-G1
- Marking Symbol: K3995
- Pin Name
- 1. Gate
- 2. Drain
- 3. Source

Internal Connection

Note) \*1: PW  $\leq 10 \ \mu s$ , Duty  $\leq 1.0\%$ 

\*2: Avalanche energy capability guaranteed

\*3: Without heat sink

# Electrical Characteristics $T_C = 25^{\circ}C \pm 3^{\circ}C$

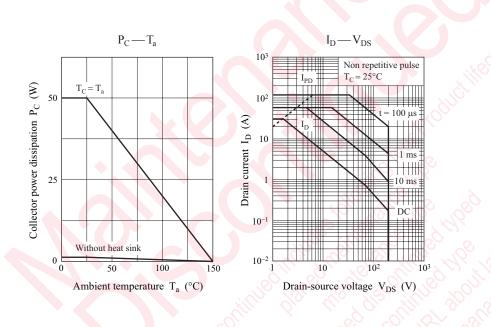
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Drain-source surrender voltage	V <sub>DSS</sub>	$I_{\rm D} = 1 \text{ mA}, V_{\rm GS} = 0$	200			V
Drain-source cutoff current	I <sub>DSS</sub>	$V_{\rm DS} = 160 \text{ V}, V_{\rm GS} = 0$			10	μΑ
Gate-source cutoff current	I <sub>GSS</sub>	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0$			±1.0	μΑ
Gate threshold voltage	V <sub>th</sub>	$V_{\rm DS} = 10 \text{ V}, I_{\rm D} = 1.0 \text{ mA}$	2.5		4.5	V
Drain-source ON resistance	R <sub>DS(on)</sub>	$V_{GS} = 10 \text{ V}, I_D = 15.0 \text{ A}$		43	52	mΩ
Forward transfer conductance	$ Y_{fs} $	$V_{\rm DS} = 10$ V, $I_{\rm D} = 15.0$ A	12	22		S
Short-circuit input capacitance (Common source)	C <sub>iss</sub>			1970		pF
Short-circuit output capacitance (Common source)	C <sub>oss</sub>	$V_{DS} = 25 V, V_{GS} = 0, f = 1 MHz$		400		pF
Reverse transfer capacitance (Common source)	C <sub>rss</sub>			85		pF
Turn-on delay time	t <sub>d(on)</sub>			32		ns
Rise time	t <sub>r</sub>	$V_{DD} = 100 \text{ V}, I_D = 15.0 \text{ A}$		130		ns
Turn-off delay time	t <sub>d(off)</sub>	$R_{\rm L} = 6.7 \Omega,  V_{\rm GS} = 10 V$		170		ns
Fall time	t <sub>f</sub>			88		ns

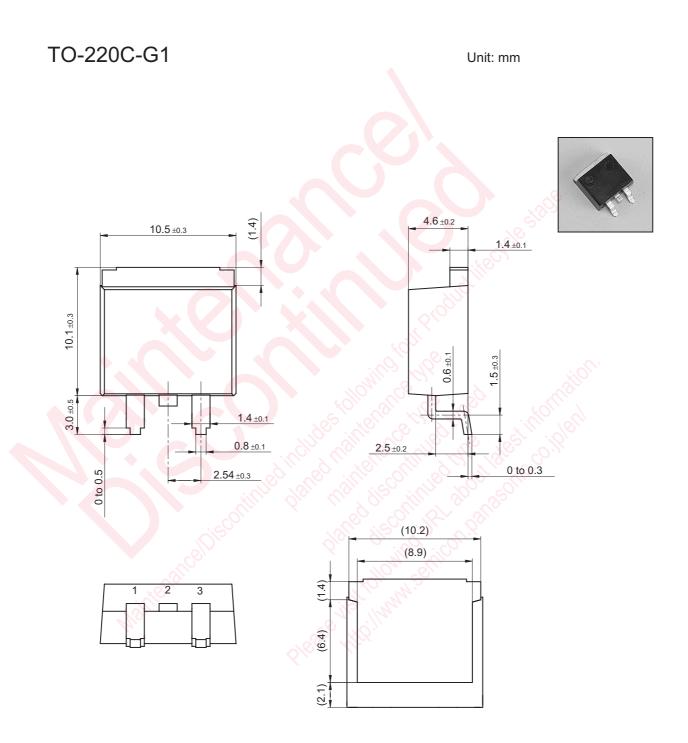
Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

## Electrical Characteristics (continued) $T_C = 25^{\circ}C \pm 3^{\circ}C$

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Diode forward voltage	V <sub>DSF</sub>	$I_{DR} = 30 \text{ A}, V_{GS} = 0$			-1.5	V
Reverse recovery time	t <sub>rr</sub>	$L = 230 \mu H, V_{DD} = 100 V$		220		ns
Reverse recovery charge	Q <sub>rr</sub>	$I_{DR} = 15.0 \text{ A}, d_i / d_t = 100 \text{ A}/\mu\text{s}$		1.1		μC
Gate charge load	Qg			66		nC
Gate-source charge	Q <sub>gs</sub>	$V_{DD} = 100 \text{ V}, I_D = 15.0 \text{ A}, V_{GS} = 10 \text{ V}$		11		nC
Gate-drain charge	Q <sub>gd</sub>			37		nC
Thermal resistance (ch-c)	R <sub>th(ch-c)</sub>				2.5	°C/W
Thermal resistance (ch-a)	R <sub>th(ch-a)</sub>				89.2	°C/W

Note) Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.





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